

10628071\_CLS.txt  
Most Frequently Occurring Classifications of Patents Returned  
From A Search of 10628071 on September 14, 2004

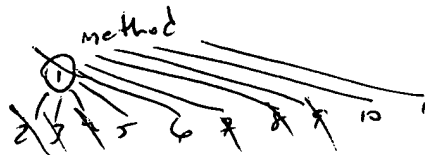
Original Classifications

3 345/600  
2 119/223  
2 324/754  
2 358/518  
2 358/520  
2 382/230

4/15/98

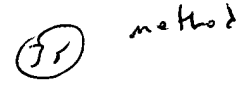
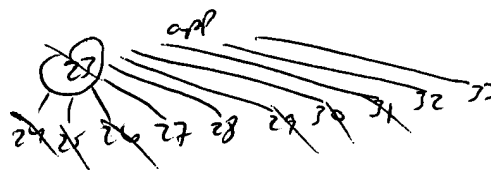
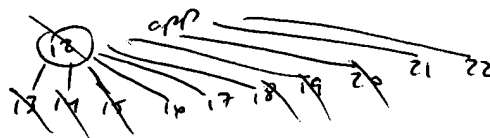
Cross-Reference Classifications

4 358/518  
3 324/73.1  
3 358/504  
2 257/E21.551  
2 257/E21.571  
2 257/E21.697  
2 257/E27.012  
2 345/604  
2 358/1.9  
2 358/520  
2 358/523  
2 382/167



Combined Classifications

6 358/518  
4 345/600  
4 358/520  
3 324/73.1  
3 324/754  
3 358/1.9  
3 358/504  
3 382/167  
2 119/223  
2 257/E21.551  
2 257/E21.571  
2 257/E21.697  
2 257/E27.012  
2 345/604  
2 358/523  
2 382/230



"logic"  
101  
problem!

10628071\_CLSTITLES.txt  
Titles of Most Frequently Occurring Classifications of Patents Returned  
From A Search of 10628071 on September 14, 2004

6	358/518	(2 OR, 4 XR)	
	Class 358 :	FACSIMILE AND STATIC PRESENTATION PROCESSING	
	358/500	NATURAL COLOR FACSIMILE	
	358/518	.Color correction	
4	345/600	(3 OR, 1 XR)	
	Class 345 :	COMPUTER GRAPHICS PROCESSING, OPERATOR INTERFACE PROCESSING, AND SELECTIVE VISUAL DISPLAY SYSTEMS	
	345/418	COMPUTER GRAPHICS PROCESSING	
	345/581	.Attributes (surface detail or characteristic, display attributes)	
	345/589	..Color or intensity	
	345/600	...Color bit data modification or conversion	
4	358/520	(2 OR, 2 XR)	
	Class 358 :	FACSIMILE AND STATIC PRESENTATION PROCESSING	
	358/500	NATURAL COLOR FACSIMILE	
	358/518	.Color correction	
	358/520	..Hue, saturation and luminance	
3	324/73.1	(0 OR, 3 XR)	
	Class 324 :	ELECTRICITY: MEASURING AND TESTING	
	324/73.1	PLURAL, AUTOMATICALLY SEQUENTIAL TESTS	
3	324/754	(2 OR, 1 XR)	
	Class 324 :	ELECTRICITY: MEASURING AND TESTING	
	324/500	FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS	
	324/537	.of individual circuit component or element	
	324/754	..With probe elements	
3	358/1.9	(1 OR, 2 XR)	
	Class 358 :	FACSIMILE AND STATIC PRESENTATION PROCESSING	
	358/1.1	STATIC PRESENTATION PROCESSING (E.G., PROCESSING DATA FOR PRINTER, ETC.)	
	358/1.9	.Attribute control	
3	358/504	(0 OR, 3 XR)	
	Class 358 :	FACSIMILE AND STATIC PRESENTATION PROCESSING	
	358/500	NATURAL COLOR FACSIMILE	
	358/504	.Measuring, testing, and calibrating	
3	382/167	(1 OR, 2 XR)	
	Class 382 :	IMAGE ANALYSIS	
	382/162	COLOR IMAGE PROCESSING	
	382/167	.Color correction	
2	119/223	(2 OR, 0 XR)	
	Class 119 :	ANIMAL HUSBANDRY	
	119/200	AQUATIC ANIMAL CULTURING	
	119/215	.Fish culturing	
	119/223	..Floating fish rearing assembly	
2	257/E21.551	(0 OR, 2 XR)	

10628071\_CLSTITLES.txt

Class 257 : ACTIVE SOLID-STATE DEVICES  
257/E21.531 ...For electrical parameters, e.g.,  
electrical means resistance, deep-levels, CV, diffusions by  
(EPO)  
257/E21.532 .Manufacture or treatment of devices  
formed in consisting of plurality of solid-state components  
or on common substrate or of parts thereof;  
manufacture of integrated circuit devices or of parts thereof (EPO)

257/E21.536 ..Manufacture of specific parts of devices  
(EPO)  
257/E21.54 ...Making of isolation regions between  
components (EPO)  
257/E21.545 ....Dielectric regions, e.g., EPIC dielectric  
isolation, LOCOS; trench refilling techniques, SOI  
technology, use of channel stoppers (EPO)  
257/E21.546 .....Using trench refilling with dielectric  
materials (EPO)  
257/E21.551 .....Introducing impurities in trench side or  
bottom walls, e.g., for forming channel stoppers or alter  
isolation behavior (EPO)

2 257/E21.571 (0 OR, 2 XR)  
Class 257 : ACTIVE SOLID-STATE DEVICES  
257/E21.531 ...For electrical parameters, e.g.,  
electrical means resistance, deep-levels, CV, diffusions by  
(EPO)  
257/E21.532 .Manufacture or treatment of devices  
formed in consisting of plurality of solid-state components  
or on common substrate or of parts thereof;  
manufacture of integrated circuit devices or of parts thereof (EPO)

257/E21.536 ..Manufacture of specific parts of devices  
(EPO)  
257/E21.54 ...Making of isolation regions between  
components (EPO)  
257/E21.545 ....Dielectric regions, e.g., EPIC dielectric  
isolation, LOCOS; trench refilling techniques, SOI  
technology, use of channel stoppers (EPO)  
257/E21.571 .....Using selective deposition of single  
crystal silicon, i.e., SEG technique (EPO)

2 257/E21.697 (0 OR, 2 XR)  
Class 257 : ACTIVE SOLID-STATE DEVICES  
Could not find subclass title.

2 257/E27.012 (0 OR, 2 XR)  
Class 257 : ACTIVE SOLID-STATE DEVICES  
257/E27.006 .Including piezo-electric, electro-resistive,  
or magneto-resistive component (EPO)  
257/E27.009 .Including semiconductor component with at  
least one potential barrier or surface barrier adapted  
for rectifying, oscillating, amplifying, or switching, or  
including integrated passive circuit elements (EPO)

257/E27.01 ..With semiconductor substrate only (EPO)  
257/E27.011 ...Including a plurality of components in a  
non-repetitive configuration (EPO)

10628071\_CLSTITLES.txt

257/E27.012 ....Made of compound semiconductor material,  
e.g. III-V material (EPO)

2 345/604 (0 OR, 2 XR)  
Class 345 : COMPUTER GRAPHICS PROCESSING, OPERATOR  
INTERFACE PROCESSING, AND SELECTIVE VISUAL DISPLAY  
SYSTEMS  
345/418 COMPUTER GRAPHICS PROCESSING  
345/581 .Attributes (surface detail or characteristic,  
display attributes)  
345/589 ..Color or intensity  
345/600 ...Color bit data modification or conversion  
345/604 ....Color space transformation (e.g., RGB to  
YUV)

2 358/523 (0 OR, 2 XR)  
Class 358 : FACSIMILE AND STATIC PRESENTATION PROCESSING  
358/500 NATURAL COLOR FACSIMILE  
358/518 .Color correction  
358/523 ..With memory for storage of conversion data

2 382/230 (2 OR, 0 XR)  
Class 382 : IMAGE ANALYSIS  
382/181 PATTERN RECOGNITION  
382/229 .Context analysis or word recognition (e.g.,  
character string)  
382/230 ..Trigrams or digrams

PLUS Search Results for S/N 10628071, Searched September 14, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

5801527  
5978107  
5883632  
6128022  
6160644  
6181445  
4351268  
4380213  
4386844  
5510910  
5798966  
5978860  
6069982  
6169762  
4246600  
4583055  
4593458  
4859633  
4991002  
5250461  
5250837  
5457785  
5479536  
5495544  
5517040  
5561377  
5570002  
5572632  
5583666  
5604843  
5610925  
5613951  
5655269  
5724449  
5748176  
5775825  
5777811  
5806897  
5841304  
5841992  
5900759  
5943577  
6008907  
6043519  
6063655  
6072901  
6088038  
6111268  
6130544  
6137495

10628071\_QUAL.txt

5801527 99  
5978107 94  
5883632 88  
6128022 88  
6160644 83  
6181445 83  
4351268 77  
4380213 77  
4386844 77  
5510910 77  
5798966 77  
5978860 77  
6069982 77  
6169762 77  
4246600 72  
4583055 72  
4593458 72  
4859633 72  
4991002 72  
5250461 72  
5250837 72  
5457785 72  
5479536 72  
5495544 72  
5517040 72  
5561377 72  
5570002 72  
5572632 72  
5583666 72  
5604843 72  
5610925 72  
5613951 72  
5655269 72  
5724449 72  
5748176 72  
5775825 72  
5777811 72  
5806897 72  
5841304 72  
5841992 72  
5900759 72  
5943577 72  
6008907 72  
6043519 72  
6063655 72  
6072901 72  
6088038 72  
6111268 72  
6130544 72  
6137495 72